

U.S. Department of Commerce, Patent and Trademark Office		Docket No.	Serial No.
(PTO Form 1449 modified)		YOR920030477US1	Unknown
INFORMATION DISCLOSURE STATEMENT BY APPLICANT		Applicant Abraham, D.	Confirmation No.:
(Use several sheets if necessary)		Filing Date	Group
Examiner		Herewith	

U.S. Patent Documents

*Examiner Initial		Document Number	Issue Date	Applicant(s) Name	Class	Subclass	Filing Date If Appropriate
DS	A1	5,065,103	11/12/1991	Slinkman et al.	324	458	
DS	A2	5,308,974	05/03/1994	Elings et al.	250	234	
DS	A3	5,612,491	03/18/1997	Lindsay	73	105	
DS	A4	5,900,728	05/04/1999	Moser, et al.	324	244	
DS	A5	5,900,729	05/04/1999	Moser et al.	324	244	
	A6						
	A7						
	A8						
	A9						
	A10						

Foreign Patent Documents

*Examiner Initial		Document Number	Date	Country	Class	Subclass	Translation	
							YES	NO
	B1						<input type="checkbox"/>	<input type="checkbox"/>
	B2						<input type="checkbox"/>	<input type="checkbox"/>
	B3						<input type="checkbox"/>	<input type="checkbox"/>
	B4						<input type="checkbox"/>	<input type="checkbox"/>

OTHER ART

*Examiner Initial		Including Author, Title, Date, Pertinent Pages, Etc.
DS	C1	Rugar, et al., "Magnetic force microscopy: General Principles and application to longitudinal recording media," J. Appl. Phys., 68(3), 1 August 1990, 1169-1183
DS	C2	Schonenberger, et al, "Understanding magnetic force microscopy," Z. Phys. B. - Condensed Matter 80, 373-383, (1990)
DS	C3	Williams, et al., "Lateral dopant profiling on a 100nm scale by scanning capacitance microscopy," J. Vac. Sci. Technol. A., 8 (2), Mar/Apr 1990, 895-898

Examiner David Schindler Date Considered 7/14/05

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.